| Ref # | Hits | Search Query | DBs | Default Operator | Plurals | Time Stamp |
|---|---|---|---|---|---|---|
| L1 | 2394 | (((((356/237.1 or 356/237.2) or 356/237.3) or 356/237.4) or 356/237.5) or 356/237.6) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/09/06 11:44 |
| L2 | 1150 | 356/237.1 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/09/06 11:45 |
| L3 | 64 | 1 and in near situ | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/09/06 11:45 |
| L4 | 46 | 3 and particles | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/09/06 11:56 |
| L5 | 0 | film near2 peel$3 and 4 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/09/06 11:46 |
| L6 | 0 | film near2 peel$3 and 3 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/09/06 11:46 |
| L7 | 9 | film near2 peel$3 and 1 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/09/06 11:46 |
| L8 | 19 | situ near2 method and ((detect$3 or measur$3) or monitor$3) near15 ((particle or defect) near6 semiconductor) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/09/06 12:02 |
| L9 | 23 | situ near2 method and ((detect$3 or measur$3) or monitor$3) near15 ((particle or defect)) and compar$3 near9 threshold | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/09/06 12:13 |
| L10 | 0 | situ and ((detect$3 or measur$3) near9 particles) and film near2 pell$3 and react$3 near2 chamber and compar$3 near9 threshold | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/09/06 12:15 |

| L11 | 0 | situ and ((detect$3 or measur$3) near9 particles) and film near2 peel$3 and react$3 near2 chamber and compar$3 near9 threshold | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/09/06 12:15 |
|---|---|---|---|---|---|---|
| L12 | 19 | situ and ((detect$3 or measur$3) near9 particles) and react$3 near2 chamber and compar$3 near9 threshold | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/09/06 12:16 |
| L13 | 39 | situ and (detect$3 or measur$3) near9 (particles near6 (wafer or substrate)) and compar$3 near9 threshold | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/09/06 12:17 |
| L14 | 17 | 13 and wavelength | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/09/06 12:21 |
| L15 | 0 | 13 and predetermin$3 near2 wavelength | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/09/06 12:18 |
| L16 | 1 | (predetermin$2 near1 wavelength) near5 (particles near6 (wafer or substrate)) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/09/06 12:22 |
| L17 | 62 | (predetermin$2 near1 wavelength) near5 (particles) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/09/06 12:23 |
| L18 | 71889 | measur$3 near6 intensity | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/09/06 12:23 |
| L19 | 13 | 17 and 18 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/09/06 12:25 |
| L20 | 43 | compar$ near9 (threshold near1 values) and (detect$3 or measur$3) near9 (particles near6 (wafer or semiconductor)) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/09/06 12:26 |

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|---|---|---|---|---|---|---|
| L21 | 120 | compar$ near9 (threshold) and (detect$3 or measur$3) near9 (particles near6 (wafer or semiconductor)) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/09/06 12:26 |
| L22 | 18 | 21 and wavelength and period near time | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/09/06 12:27 |
| L23 | 12 | 21 and wavelength and intensity near value | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/09/06 12:31 |
| L24 | 1 | yi-ling near chen | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/09/06 12:33 |
| L25 | 472 | react$3 near chamber near condition | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/09/06 12:33 |
| L26 | 37 | chamber near condition and film near2 peel$3 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/09/06 12:34 |
| L27 | 13 | 26 and particles | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/09/06 12:34 |